Notice of References Cited Application/Control No. | Applicant(s)/Patent Under | Reexamination | HUNG ET AL. | Examiner | Art Unit | Huy C. Ho | 2617 | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0196834	10-2004	Ofek et al.	370/352
*	В	US-7,130,586	10-2006	Corbett et al.	455/63.4
*	С	US-2004/0145530	07-2004	Foore et al.	343/754
*	D	US-2003/0181221	09-2003	Nguyen, Hung	455/562.1
*	E	US-2004/0130487	07-2004	Hoffmann et al.	342/359
*	F	US-7,068,977	06-2006	Yang et al.	455/67.13
*	G	US-7,058,146	06-2006	Paulraj et al.	375/347
*	Н	US-2002/0181492	12-2002	Kasami et al.	370/445
*	ı	US-2003/0179138	09-2003	Chen, Michael	342/372
*	J	US-2002/0147031	10-2002	Hood, Charles D. III	455/562
*	к	US-2005/0156800	07-2005	Sankaranarayanan, Ravishankar	343/753
*	L	US-2002/0085653	07-2002	Matsuoka et al.	375/347
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
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	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	·
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	w	·
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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